L Number	Hits	Search Text	DB	Time stamp
1	0	(5404358.pn.) and chain	USPAT; US-PGPUB;	2004/04/13 13:58
2	1	(5404358.pn.) and serial\$2	EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/04/13 14:02
3	1	(5404358.pn.) and serial\$2 and switch\$3	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/04/13
4	5	(second adj scan adj register\$1) and chain\$1	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/04/13 14:39
5	35	scan adj register\$1 adj chain\$1	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/04/13
6	1	(scan adj register\$1 adj chain\$1) with bypass\$3	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:20
7	93	(scan adj chain\$1) with bypass\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:21
8	36	(scan adj chain\$1) with register with bypass\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13
9	0	(scan adj chain\$1) with bypass\$3 with switch\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13
10	3	(scan with chain\$1) with bypass\$3 with switch\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:27
11	2	((scan with chain\$1) with bypass\$3 with switch\$3) and (semiconductor or IC)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13
12	4	((register with chain\$1) with bypass\$3 with switch\$3) and (semiconductor or IC)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13
13	2	5491666.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/04/13 17:39
14	3	6708304.pn.	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/04/13 17:39

Search History

4/13/04 5:45:40 PM

-	2	20020144200.pn.	USPAT;	2004/04/05
			US-PGPUB;	15:46
			EPO; JPO;	
		·	DERWENT;	
		(714/706 \d	IBM_TDB	2004/04/05
-	0	(714/726.pn.) and scan\$4 and test\$3 and	USPAT;	15:50
		<pre>(semiconductor\$1 or (integrated adj circuit\$1) or IC) and analog and</pre>	US-PGPUB; EPO; JPO;	15:50
		(internal adj circuit) and pin\$1 and	DERWENT;	
		(scan adj register\$1) and (input adj	IBM TDB	
		output)	1511_155	
_	13	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/05
	13	(integrated adj circuit\$1) or IC) and	US-PGPUB;	15:59
ļ		analog and (internal adj circuit) and	EPO; JPO;	
		pin\$1 and (scan adj register\$1) and	DERWENT;	
ļ		(input adj output)	IBM TDB	
_	4	scan\$4 and test\$3 and (semiconductor\$1 or	USPĀT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:00
		analog and (internal adj circuit) and	EPO; JPO;	
		pin\$1 and (scan adj register\$1) and	DERWENT;	
		(input adj output) and (short with	IBM_TDB	
		wiring)		
-	2	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:01
		analog and (internal adj circuit) and	EPO; JPO;	
		pin\$1 and (scan adj register\$1) and	DERWENT;	
		(input adj output) and (analog with	IBM_TDB	
1		<pre>wiring) scan\$4 and test\$3 and (semiconductor\$1 or</pre>	HCDAM.	2004/04/08
-	6	(integrated adj circuit\$1) or IC) and	USPAT; US-PGPUB;	11:06
		analog and (internal adj circuit) and	EPO; JPO;	11.00
		pin\$1 and (scan adj register\$1) and	DERWENT;	
	ļ	(input adj output) and (analog with	IBM TDB	
		input)	15	
_	2	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
	_	(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:07
		(internal adj circuit) and pin\$1 and	EPO; JPO;	
İ	İ	(scan adj register\$1) and (input adj	DERWENT;	
		output) and (analog with pin\$1)	IBM_TDB	
-	32	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	16:35
		pin\$1 and (scan adj register\$1) and	EPO; JPO;	
		(input adj output) and (analog with	DERWENT;]
		pin\$1)	IBM_TDB	2004/04/08
-	22	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT; US-PGPUB;	17:28
		(integrated adj circuit\$1) or IC) and pin\$1 and (scan adj register\$1) and	EPO; JPO;	11.20
1		(input adj output) and (analog with	DERWENT;	
	1	pin\$1) and (JTAG with scan\$4)	IBM TDB	
_	2		USPAT;	2004/04/08
	"	(integrated adj circuit\$1) or IC) and	US-PGPUB;	14:56
		pin\$1 and ((scan adj register\$1) with	EPO; JPO;	
		((input adj output) adj pin)) and (analog	DERWENT;	
		with pin\$1)	IBM_TDB	
-	2	5322989.pn.	USPĀT;	2004/04/08
			US-PGPUB;	15:58
			EPO; JPO;	
			DERWENT;	
	_		IBM_TDB	2004/04/00
-	0	JP05322989.pn.	USPAT;	2004/04/08
			US-PGPUB;	15:59
-			EPO; JPO;	
			DERWENT; IBM TDB	•
1_	0	TD5322989 nn	USPAT;	2004/04/08
1 -		JP5322989.pn.	US-PGPUB;	15:59
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
1	1			

		_		
_	1	05322989.pn.	USPAT;	2004/04/08
			US-PGPUB;	16:01
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	112834	TORU.INV.	USPAT;	2004/04/08
			US-PGPUB;	16:02
			EPO; JPO;]
			DERWENT;	
			IBM TDB	
_	112834	TORU.IN.	USPĀT;	2004/04/08
			US-PGPUB;	16:02
			EPO; JPO;	4
			DERWENT;	
			IBM TDB	
_	l o	TORU-SHIONO.IN.	USPAT;	2004/04/08
			US-PGPUB;	16:03
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	2	TORU-SH\$4.IN.	USPAT;	2004/04/08
		1000 000 1000	US-PGPUB;	16:03
			EPO; JPO;	*****
			DERWENT;	
			IBM TDB	
	0	TORU-SHIONO.IN.	USPAT;	2004/04/08
-	"	TORU-SHIONU.IN.		16:06
			US-PGPUB;	16:06
1			EPO; JPO;	
			DERWENT;	
		11030001 PV	IBM_TDB	2004/04/00
_	2	11038091.PN.	USPAT;	2004/04/08
			US-PGPUB;	16:06
			EPO; JPO;	
			DERWENT;	
		20000144000	IBM_TDB	2004/04/00
-	2	20020144200.pn.	USPAT;	2004/04/08
			US-PGPUB;	16:36
			EPO; JPO;	
			DERWENT;	
	1 44		IBM_TDB	2004/04/02
T	144	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
·		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:29
		(scan adj register\$1) and (JTAG with	EPO; JPO;	
		scan\$4 with register)	DERWENT;	
	4-1		IBM_TDB	2004/04/00
_	41	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:30
		(scan adj register\$1) and (JTAG with	EPO; JPO;	
		scan\$4 with register) and (JTAG with	DERWENT;	
	_	specification)	IBM_TDB	2004/04/00
-	9	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:35
		(scan adj register\$1) and (JTAG with	EPO; JPO;	
		scan\$4 with register) and (JTAG with	DERWENT;	
		specification) and (register with chain)	IBM_TDB	
	_	and (control\$3 with (scan adj register))		0004/04/00
-	1	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:35
		(scan adj register\$1) and (JTAG adj	EPO; JPO;	
		(scan\$4 adj register)) and (JTAG with	DERWENT;	
		specification) and (register with chain)	IBM_TDB	
		and (control\$3 with (scan adj register))		